June1996



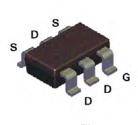
NDC632P P-Channel Logic Level Enhancement Mode Field Effect Transistor

General Description

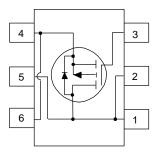
These P-Channel logic level enhancement mode power field effect transistors are produced using Fairchild's proprietary, high cell density, DMOS technology. This very high density process is especially tailored to minimize on-state resistance. These devices are particularly suited for low voltage applications such as notebook computer power management and other battery powered circuits where fast high-side switching, and low in-line power loss are needed in a very small outline surface mount package.

Features

- -2.7A, -20V. $R_{DS(ON)} = 0.14\Omega$ @ $V_{GS} = -4.5V$ $R_{DS(ON)} = 0.2\Omega$ @ $V_{GS} = -2.7V.$
- Proprietary SuperSOTTM-6 package design using copper lead frame for superior thermal and electrical capabilities.
- High density cell design for extremely low R_{DS(ON)}.
- Exceptional on-resistance and maximum DC current capability.



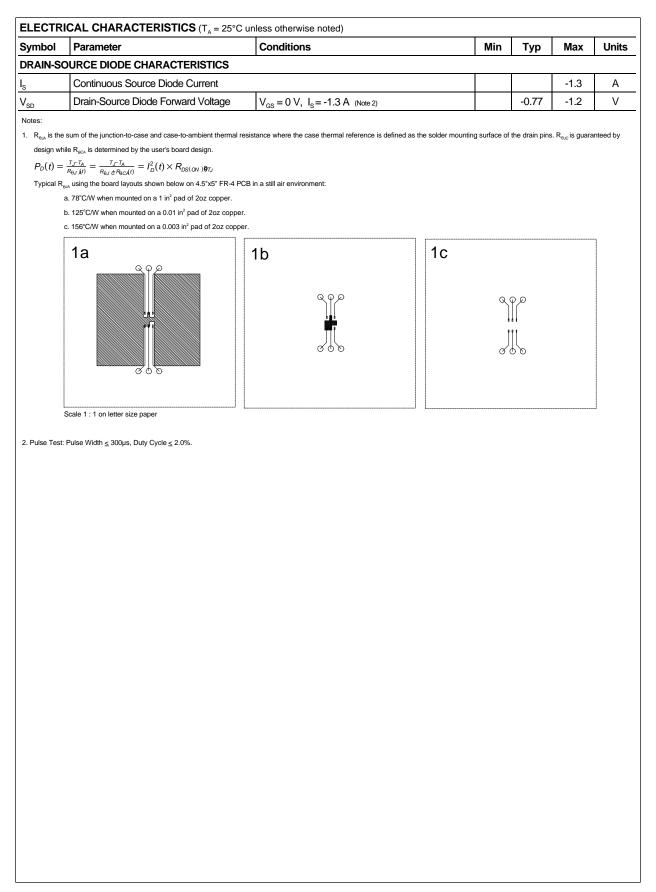
SuperSOT[™]-6

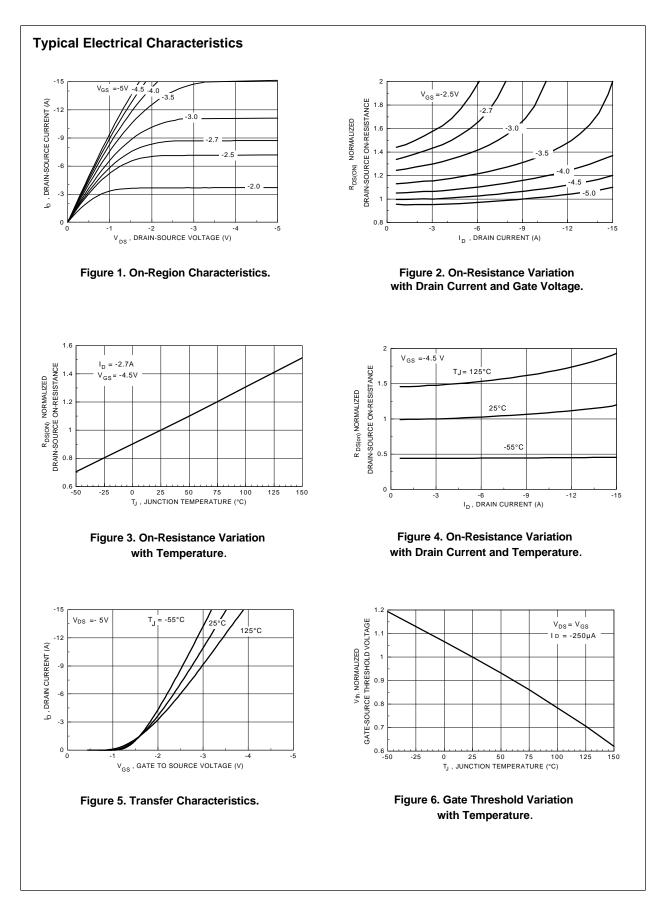


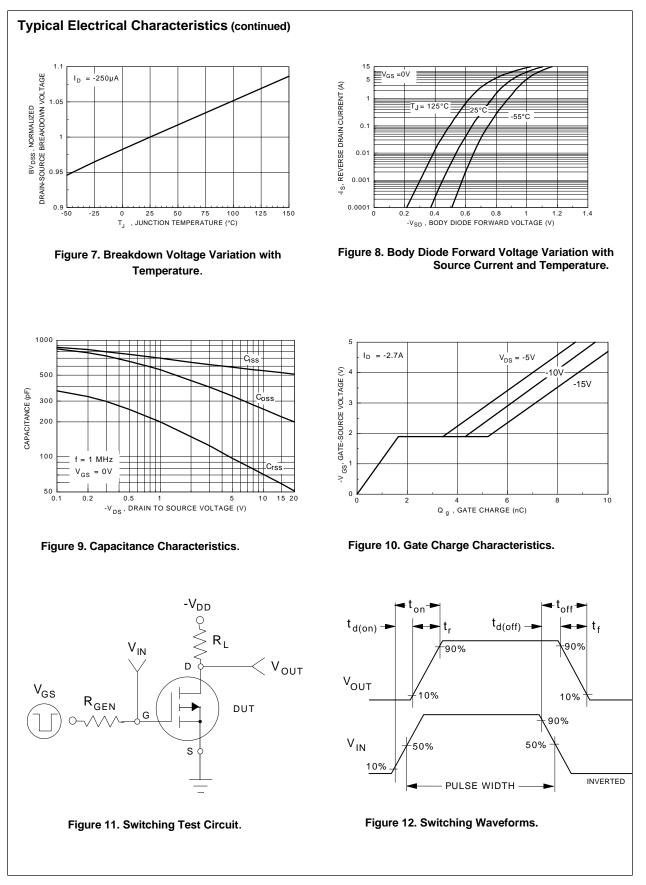
Symbol	Parameter		NDC632P	Units
V _{DSS}	Drain-Source Voltage		-20	V
V _{GSS}	Gate-Source Voltage - Continuous		-8	V
D	Drain Current - Continuous		-2.7	А
	- Pulsed		-10	
P _D	Maximum Power Dissipation	(Note 1a)	1.6	W
		(Note 1b)	1	
		(Note 1c)	0.8	
Γ _J ,T _{stg}	Operating and Storage Temperature Range		-55 to 150	°C
THERMA	AL CHARACTERISTICS			
۲ _{θJA}	Thermal Resistance, Junction-to-Ambient	(Note 1a)	78	°C/W
ج ^{ھر} ک	Thermal Resistance, Junction-to-Case	(Note 1)	30	°C/W

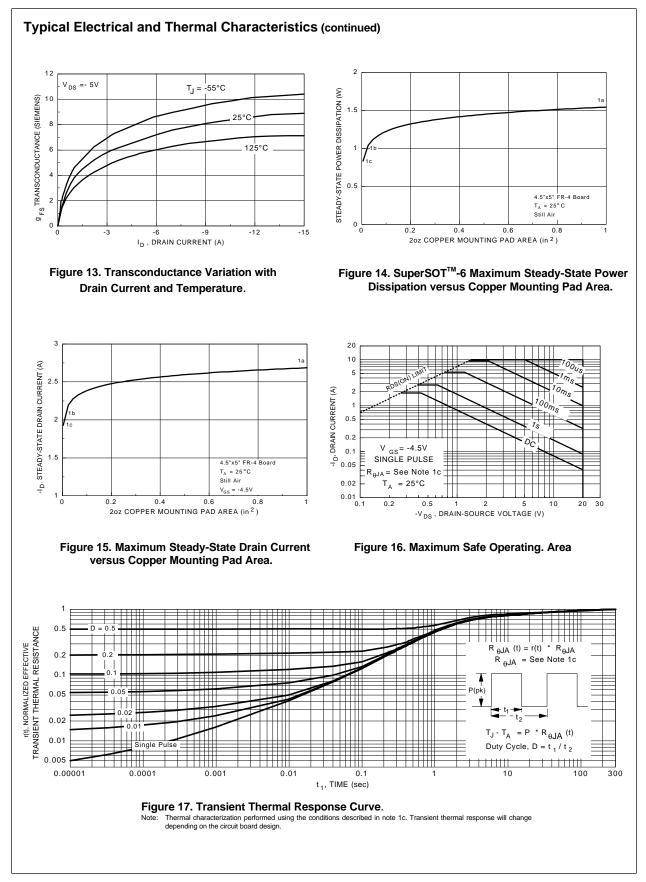
1997 Fairchild Semiconductor Corporation

Symbol	Parameter	Conditions		Min	Тур	Max	Units
OFF CHA	ARACTERISTICS						
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_{D} = -250 \mu\text{A}$		-20			V
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = -16 \text{ V}, V_{GS} = 0 \text{ V}$				-1	μA
			$T_J = 55^{\circ}C$			-10	μA
	Gate - Body Leakage, Forward	$V_{GS} = 8 V, V_{DS} = 0 V$				100	nA
I _{GSSR}	Gate - Body Leakage, Reverse	$V_{GS} = -8 V, V_{DS} = 0 V$				-100	nA
ON CHAP	RACTERISTICS (Note 2)						
V _{GS(th)}	Gate Threshold Voltage	$V_{\rm DS} = V_{\rm GS}, \ I_{\rm D} = -250 \ \mu {\rm A}$		-0.4	-0.7	-1	V
			T _J = 125°C	-0.3	-0.5	-0.8	
R _{DS(ON)}	Static Drain-Source On-Resistance	$V_{GS} = -4.5 \text{ V}, \ \text{I}_{D} = -2.7 \text{ A}$	·		0.1	0.14	Ω
			T _J = 125°C		0.145	0.28	
		$V_{GS} = -2.7 \text{ V}, \ I_{D} = -2.2 \text{ A}$	·		0.152	0.2	
I _{D(on)}	On-State Drain Current	$V_{GS} = -4.5 \text{ V}, V_{DS} = -5 \text{ V}$		-10			А
		$V_{GS} = -2.7 \text{ V}, V_{DS} = -5 \text{ V}$		-4			
9 _{FS}	Forward Transconductance	$V_{\rm DS}$ = -10 V, $I_{\rm D}$ = -2.7 A			6		S
DYNAMIC	CHARACTERISTICS						
C _{iss}	Input Capacitance	$V_{DS} = -10 V, V_{GS} = 0 V,$			550		pF
C _{oss}	Output Capacitance	f = 1.0 MHz			260		pF
C _{rss}	Reverse Transfer Capacitance				75		pF
SWITCHI	NG CHARACTERISTICS (Note 2)						
t _{D(on)}	Turn - On Delay Time	$V_{DD} = -5 V, I_{D} = -1 A,$			10	20	ns
t,	Turn - On Rise Time	V_{GEN} = -4.5 V, R_{GEN} = 6 Ω			40	60	ns
t _{D(off)}	Turn - Off Delay Time				25	40	ns
t _r	Turn - Off Fall Time				17	30	ns
Q _g	Total Gate Charge	$V_{DS} = -5 V,$ $I_{D} = -2.7 A, V_{GS} = -4.5 V$			8.7	15	nC
Q _{gs}	Gate-Source Charge				1.7		nC
Q_{gd}	Gate-Drain Charge				1.8		nC

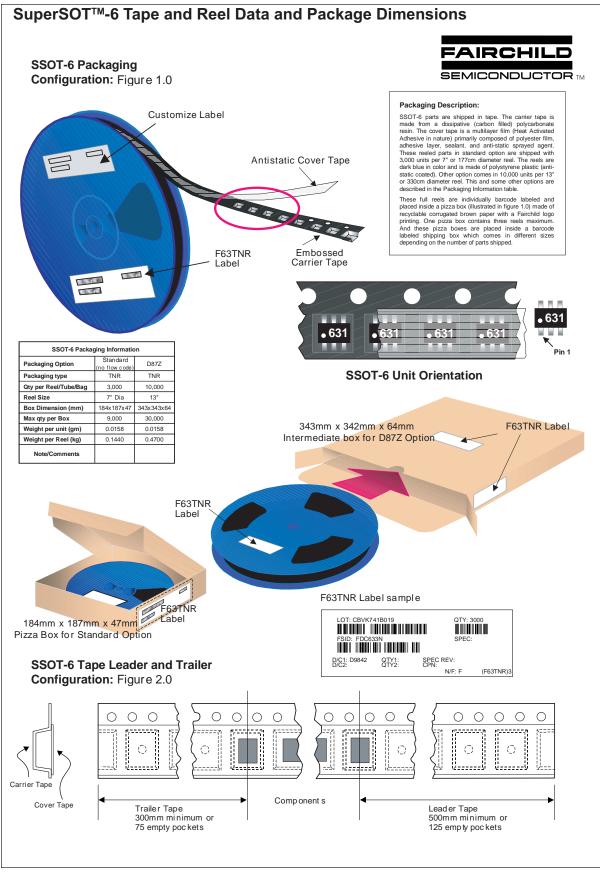




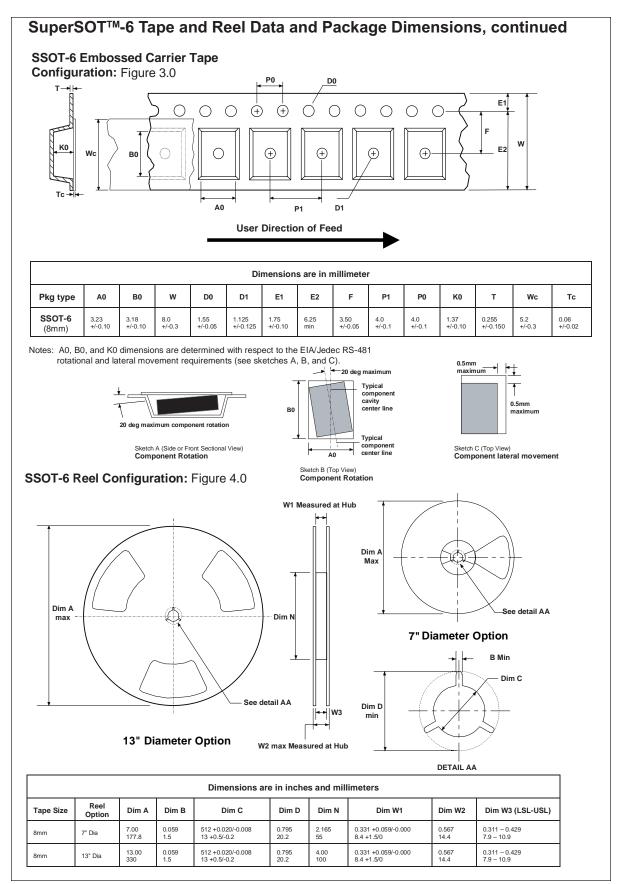




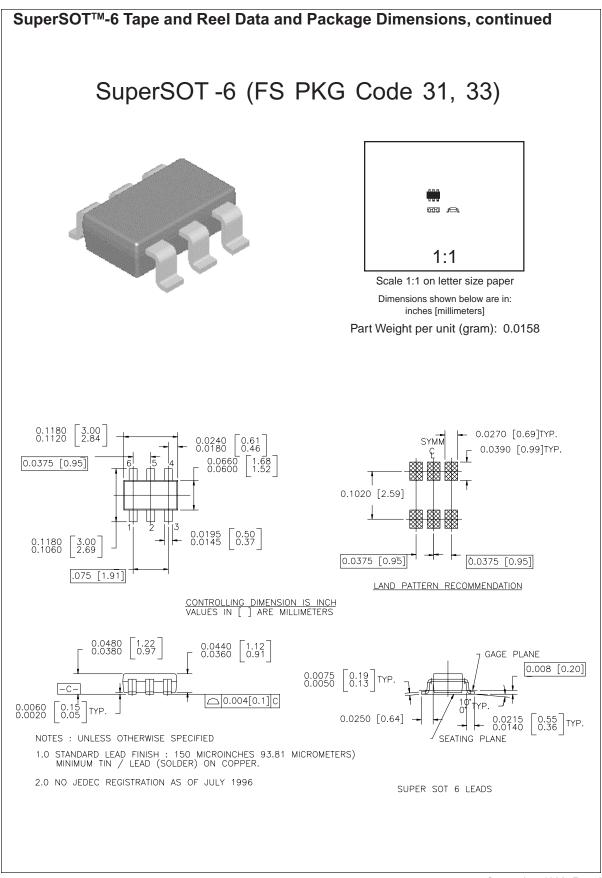
NDC632P Rev. B1



August 1999, Rev. C



July 1999, Rev. C



September 1998, Rev. A

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